

**Amendments to the Claims:**

The listing of claims will replace all prior versions and listings of claims in the application:

**5    Listing of Claims:**

Claim 1 (currently amended): A method of defect root cause analysis comprising following steps:

      providing a ~~single~~ die being processed through a plurality of semiconductor processes, wherein the ~~single~~ die comprises a plurality of defects;

10       dividing the defects into three defect types comprising a first defect type, a second defect type, and a third defect type according to their sizes and locations;

      performing a defect inspection to detect sizes and locations of the plurality of defects;

using three methods to perform ~~performing~~ a chemical state analysis.

15       corresponding to each defect type respectively of the single die;

      performing a mapping analysis according to a result of the chemical state analysis, wherein the mapping analysis comprises:

          forming the defects of the ~~single~~ die into a defect pattern; and

          comparing the defect pattern with a predetermined pattern on the ~~single~~ die;

20       analyzing the root cause of the defects according to the comparison between the defect pattern and the predetermined pattern on the ~~single~~ die for determining the semiconductor process causing the defect; and

      modifying the semiconductor process causing the defects to reduce the number of defects in the ~~single~~ die.

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Claim 2 (original): The method of claim 1 further comprising performing a defect classification after finishing the defect inspection for judging a defect type of the defects and performing a corresponding chemical state analysis according to the defect type of the defects.

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Claim 3 (original): The method of claim 1 wherein an auger analysis is performed in the chemical state analysis when the defects are smaller than  $0.2 \mu m$  or are not single phase particles.

- 5 Claim 4 (currently amended): The method of claim 3 wherein the auger analysis utilizes a scanning auger microscopy (SAM) or an auger electron spectroscopy (AES) to perform the chemical state analysis of the ~~single~~ die.

- 10 Claim 5 (original): The method of claim 1 wherein an energy dispersive spectrometer (EDS) is utilized to detect in the chemical state analysis when the defects are equal to or larger than  $0.2 \mu m$ , single phase, or thick particles.

Claim 6 (original): The method of claim 1 wherein the chemical state analysis comprises a point scan analysis, delayer analysis, and depth profile analysis.

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- Claim 7 (currently amended): A method of defect root cause analysis comprising following steps:
- providing a ~~single~~ die being processed through a plurality of semiconductor processes, wherein the ~~single~~ die comprises a plurality of defects;
- 20        performing a voltage contrast to identify locations of the defects;
- cutting the ~~single~~ die with a focus ion beam (FIB) to expose a cross-section of the ~~single~~ die;
- utilizing auger electrons to perform a chemical state analysis of the cross-section of the ~~single~~ die;
- 25        performing a mapping analysis according to a result of the chemical state analysis, wherein the mapping analysis comprises:
- forming the defects into a defect pattern; and
- comparing the defect pattern with a predetermined pattern on the ~~single~~ die;
- judging a root cause of the defect generation according to the comparison
- 30        between the defect pattern and the predetermined pattern on the ~~single~~ die for

determining the semiconductor process causing the defect; and  
modifying the semiconductor process causing the defects to reduce the number of  
defects in the ~~single~~ die.

- 5 Claim 8 (currently amended): The method of the claim 7 wherein the method utilizes a scanning auger microscopy (SAM) or an auger electron spectroscopy (AES) to perform a chemical state analysis of the cross-section of the ~~single~~ die.

- 10 Claim 9 (original): The method of claim 7 wherein the chemical state analysis comprises a point scan analysis.

Claim 10 (new): The method of claim 1, wherein the first defect type comprises defects located on an underlayer of the die.

- 15 Claim 11 (new): The method of claim 1, wherein the second defect type comprises defects located on the surface of the die and are equal to or larger than  $0.2 \mu m$ , single phase, or thick particles.

- 20 Claim 12 (new): The method of claim 1, wherein the third defect type comprises defects located on the surface of the die and are smaller than  $0.2 \mu m$ , not single phase, or not thick particles.